Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/795,770	HATAKEYAMA ET AL.	
Examiner	Art Unit	
Tamai I.E. Karl	2834	

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Class	Subclass	Date	Examiner
310	309		
385	18		
359	290,291	2/10/2006	KIT
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INT	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
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